

Applications of focused ion beam systems in gunshot residue investigation

Niewöhner L, Wenz HW.

Journal of forensic sciences

1999; 44(1):105-109

ARTICLE IDENTIFIERS

DOI: unavailable

PMID: 9987878

PMCID: not available

JOURNAL IDENTIFIERS

LCCN: not available

pISSN: 0022-1198

eISSN: 1556-4029

OCLC ID: 01754597

CONS ID: not available

US National Library of Medicine ID: 0375370

This article was identified from a query of the SafetyLit database.